

30V N-Channel Enhancement Mode MOSFET

Description

The AP100N03AD uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS}=30V I_D =100A

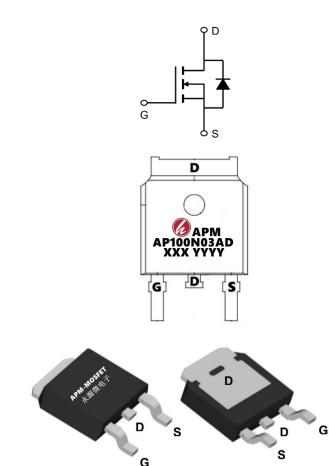
 $R_{DS(ON)} < 6.0m\Omega @ V_{GS}=10V$ (Type: 4.8m Ω)

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP100N03AD	TO-252-3L	AP100N03AD XXXX YYYY	2500

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units	
Vds	Drain-Source Voltage	30	V	
Vgs	Gate-Source Voltage	±20	V	
I⊳@Tc=25°C	Continuous Drain Current, V _{GS} @ 10V ¹	100	A	
I₀@Tc=75°C	Continuous Drain Current, V _{GS} @ 10V ¹	59	A	
Ідм	Pulsed Drain Current ²	240	A	
EAS	Single Pulse Avalanche Energy ³	Pulse Avalanche Energy ³ 56		
las	Avalanche Current	15	А	
P₀@Tc=25°C	Total Power Dissipation ⁴	46	W	
P _D @T _A =25°C	Total Power Dissipation ⁴	2.72	W	
Tstg	Storage Temperature Range	-55 to 175	°C	
TJ	Operating Junction Temperature Range	-55 to 175	°C	
Reja	Thermal Resistance Junction-Ambient ¹	62	°C/W	
Rejc	Thermal Resistance Junction-Case ¹	2.72	°C/W	

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Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units	
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _D =250µA	30	32	-	V	
IDSS	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} = 0V,	-	-	1.0	μA	
IGSS	Gate to Body Leakage Current	V_{DS} =0V, V_{GS} = ±20V	-	-	±100	nA	
VGS(th)	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D =250µA	1.0	1.5	2.5	V	
		V _{GS} =10V, I _D =30A	-	4.8	6.0	mΩ	
RDS(on)	Static Drain-Source on-Resistance	V _{GS} =4.5V, I _D =20A	-	7.5	12		
Ciss	Input Capacitance		-	1614	-	pF	
Coss	Output Capacitance	V _{DS} =15V, V _{GS} =0V, f = 1.0MHz	-	245	-	pF	
Crss	Reverse Transfer Capacitance		-	215	-	pF	
Qg	Total Gate Charge		-	33.7	-	nC	
Qgs	Gate-Source Charge	V _{DS} =15V, I _D =30A, V _{GS} =10V	-	8.5	-	nC	
Qgd	Gate-Drain("Miller") Charge		-	7.5	-	nC	
td(on)	Turn-on Delay Time		-	7.5	-	ns	
tr	Turn-on Rise Time	V _{DS} =15V, I _D =30A, R _{GEN} =3Ω,	-	14.5	-	ns	
td(off)	Turn-off Delay Time	$V_{GS} = 10V$	-	35.2	-	ns	
tr	Turn-off Fall Time		-	9.6	-	ns	
IS	Maximum Continuous Drain to Source Diode Forward Current			-	70	А	
ISM	Maximum Pulsed Drain to Source Di	mum Pulsed Drain to Source Diode Forward Current			280	А	
VSD	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _S =30A	-	-	1.2	V	

Note :

1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.

2、 The data tested by pulsed , pulse width $\leq 300 us$, duty cycle $\leq 2\%$

3、The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1mH,IAS=15A

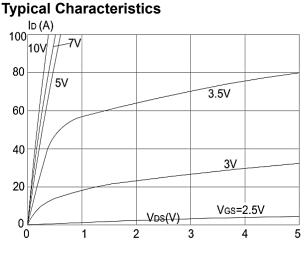
4. The power dissipation is limited by $175^{\circ}C$ junction temperature

5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

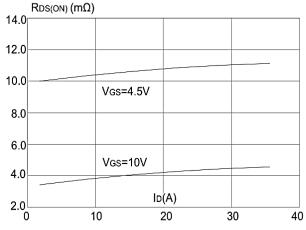




30V N-Channel Enhancement Mode MOSFET







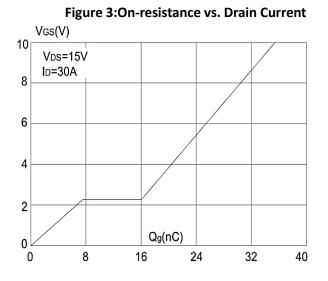


Figure 5: Gate Charge Characteristics

AP100N03AD RVE1.0

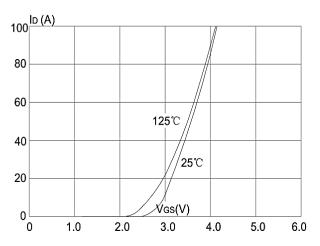


Figure 2: Typical Transfer Characteristics

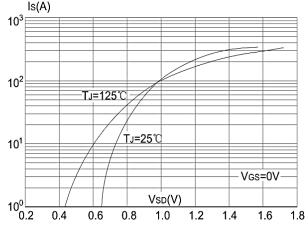


Figure 4: Body Diode Characteristics

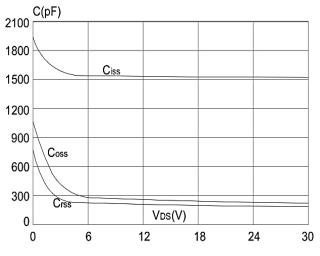


Figure 6: Capacitance Characteristics

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30V N-Channel Enhancement Mode MOSFET

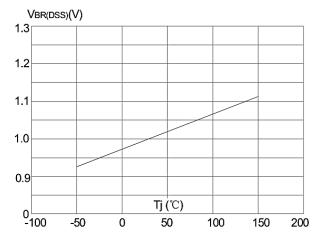


Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

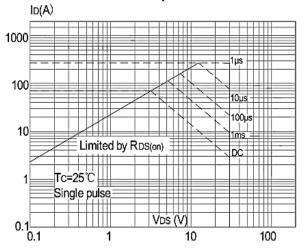


Figure 9: Maximum Safe Operating Area vs. Case Temperature

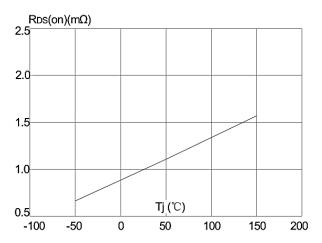


Figure 8: Normalized on Resistance vs Junction Temperature

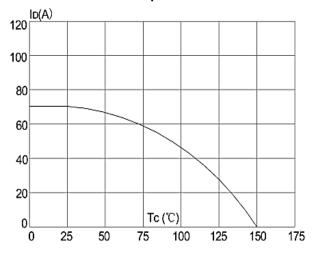


Figure 10: Maximum Continuous Drain Current

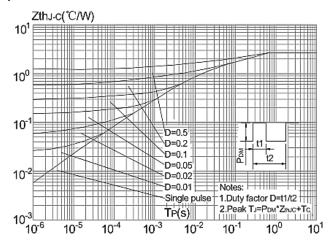


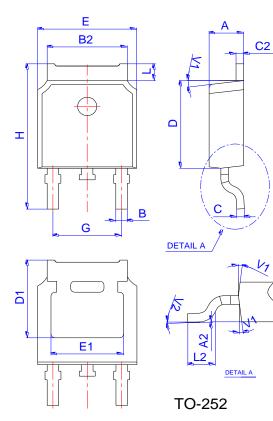
Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ca





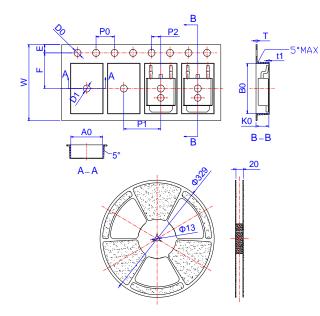
30V N-Channel Enhancement Mode MOSFET

Package Mechanical Data:TO-252-3L



	Dimensions					
Ref.		Millimeters		Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
В	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
С	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
н	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Spectification-TO-252



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
Е	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

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Edition	Date	Change
Rve1.0	2021/5/1	Initial release

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